FAIRCHILD

SEMICONDUCTOR™

October 1987
Revised March 2002

CD4001BC/CD4011BC
Quad 2-Input NOR Buffered B Series Gate •
Quad 2-Input NAND Buffered B Series Gate

General Description

The CD4001BC and CD4011BC quad gates are monolithic complementary MOS (CMOS) integrated circuits constructed with N- and P-channel enhancement mode transistors. They have equal source and sink current capabilities and conform to standard B series output drive. The devices also have buffered outputs which improve transfer characteristics by providing very high gain.

All inputs are protected against static discharge with diodes to V_{DD} and V_{SS}.

Features

■ Low power TTL:
   Fan out of 2 driving 74L compatibility: or 1 driving 74LS
■ 5V–10V–15V parametric ratings
■ Symmetrical output characteristics
■ Maximum input leakage 1 μA at 15V over full temperature range

Ordering Code:

| Order Number	Package Number	Package Description
CD4001BCM	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
CD4001BCSJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
CD4001BCN	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
CD4011BCM	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
CD4011BCN	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.
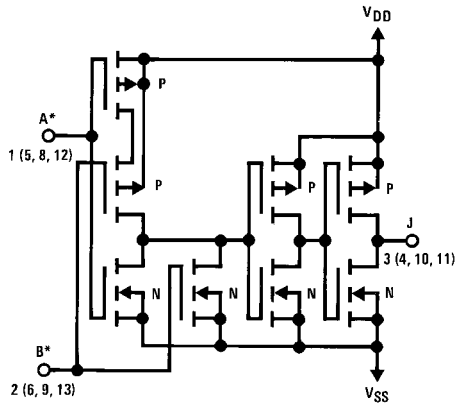
Connection Diagrams

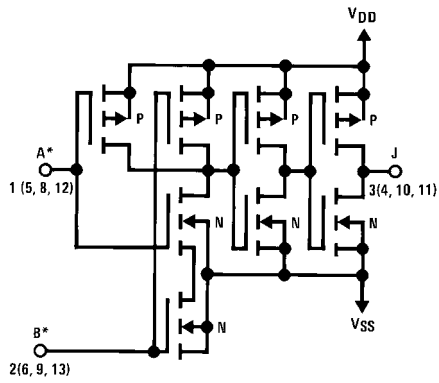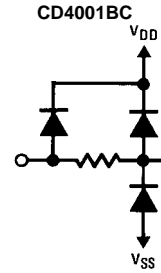**Pin Assignments for DIP, SOIC and SOP
CD4001BC**

Top View
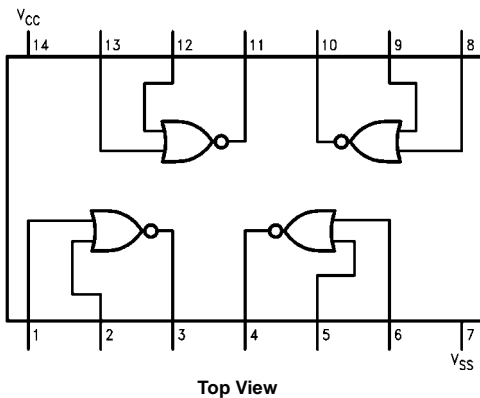
**Pin Assignments for DIP and SOIC
CD4011BC**

Top View
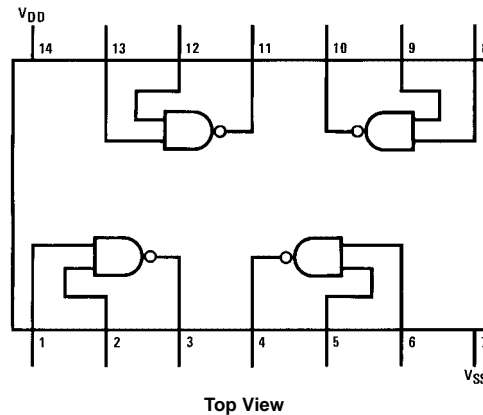
Schematic Diagrams

CD4001BC
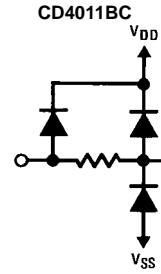

$^1/_4$ **of device shown**

$J = \overline{A + B}$

Logical "1" = HIGH

Logical "0" = LOW

All inputs protected by standard CMOS protection circuit.

CD4011BC

$^1/_4$ **of device shown**

$J = \overline{A \cdot B}$

Logical "1" = HIGH

Logical "0" = LOW

All inputs protected by standard CMOS protection circuit.

Absolute Maximum Ratings(Note 1)

(Note 2)

Voltage at any Pin	−0.5V to V_{DD} +0.5V
Power Dissipation (P_D)	
Dual-In-Line	700 mW
Small Outline	500 mW
V_{DD} Range	−0.5 V_{DC} to +18 V_{DC}
Storage Temperature (T_S)	−65°C to +150°C
Lead Temperature (T_L)	
(Soldering, 10 seconds)	260°C

Recommended Operating Conditions

Operating Range (V_{DD})	3 V_{DC} to 15 V_{DC}
Operating Temperature Range	
CD4001BC, CD4011BC	−55°C to +125°C

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The Electrical Characteristics tables provide conditions for actual device operation.

Note 2: All voltages measured with respect to V_{SS} unless otherwise specified.

DC Electrical Characteristics (Note 2)

Symbol	Parameter	Conditions	−55°C Min	−55°C Max	+25°C Min	+25°C Typ	+25°C Max	+125°C Min	+125°C Max	Units
I_{DD}	Quiescent Device	V_{DD} = 5V, V_{IN} = V_{DD} or V_{SS}		0.25		0.004	0.25		7.5	
	Current	V_{DD} = 10V, V_{IN} = V_{DD} or V_{SS}		0.5		0.005	0.50		15	μA
		V_{DD} = 15V, V_{IN} = V_{DD} or V_{SS}		1.0		0.006	1.0		30	
V_{OL}	LOW Level	V_{DD} = 5V		0.05		0	0.05		0.05	
	Output Voltage	V_{DD} = 10V $|I_O|$ < 1 μA		0.05		0	0.05		0.05	V
		V_{DD} = 15V		0.05		0	0.05		0.05	
V_{OH}	HIGH Level	V_{DD} = 5V	4.95		4.95	5		4.95		
	Output Voltage	V_{DD} = 10V $|I_O|$ < 1 μA	9.95		9.95	10		9.95		V
		V_{DD} = 15V	14.95		14.95	15		14.95		
V_{IL}	LOW Level	V_{DD} = 5V, V_O = 4.5V		1.5		2	1.5		1.5	
	Input Voltage	V_{DD} = 10V, V_O = 9.0V		3.0		4	3.0		3.0	V
		V_{DD} = 15V, V_O = 13.5V		4.0		6	4.0		4.0	
V_{IH}	HIGH Level	V_{DD} = 5V, V_O = 0.5V	3.5		3.5	3		3.5		
	Input Voltage	V_{DD} = 10V, V_O = 1.0V	7.0		7.0	6		7.0		V
		V_{DD} = 15V, V_O = 1.5V	11.0		11.0	9		11.0		
I_{OL}	LOW Level Output	V_{DD} = 5V, V_O = 0.4V	0.64		0.51	0.88		0.36		
	Current	V_{DD} = 10V, V_O = 0.5V	1.6		1.3	2.25		0.9		mA
	(Note 3)	V_{DD} = 15V, V_O = 1.5V	4.2		3.4	8.8		2.4		
I_{OH}	HIGH Level Output	V_{DD} = 5V, V_O = 4.6V	−0.64		−0.51	−0.88		−0.36		
	Current	V_{DD} = 10V, V_O = 9.5V	−1.6		−1.3	−2.25		−0.9		mA
	(Note 3)	V_{DD} = 15V, V_O = 13.5V	−4.2		−3.4	−8.8		−2.4		
I_{IN}	Input Current	V_{DD} = 15V, V_{IN} = 0V		−0.10		-10^{-5}	−0.10		−1.0	μA
		V_{DD} = 15V, V_{IN} = 15V		0.1		10^{-5}	0.10		1.0	

Note 3: I_{OL} and I_{OH} are tested one output at a time.

AC Electrical Characteristics (Note 4)

CD4001BC: T_A = 25°C, Input t_r; t_f = 20 ns. C_L = 50 pF, R_L = 200k. Typical temperature coefficient is 0.3%/°C.

Symbol	Parameter	Conditions	Typ	Max	Units
t_{PHL}	Propagation Delay Time,	V_{DD} = 5V	120	250	
	HIGH-to-LOW Level	V_{DD} = 10V	50	100	ns
		V_{DD} = 15V	35	70	
t_{PLH}	Propagation Delay Time,	V_{DD} = 5V	110	250	
	LOW-to-HIGH Level	V_{DD} = 10V	50	100	ns
		V_{DD} = 15V	35	70	
t_{THL}, t_{TLH}	Transition Time	V_{DD} = 5V	90	200	
		V_{DD} = 10V	50	100	ns
		V_{DD} = 15V	40	80	
C_{IN}	Average Input Capacitance	Any Input	5	7.5	pF
C_{PD}	Power Dissipation Capacity	Any Gate	14		pF

Note 4: AC Parameters are guaranteed by DC correlated testing.

AC Electrical Characteristics (Note 5)

CD4011BC: T_A= 25°C, Input t_r; t_f = 20 ns. C_L = 50 pF, R_L = 200k. Typical Temperature Coefficient is 0.3%/°C.

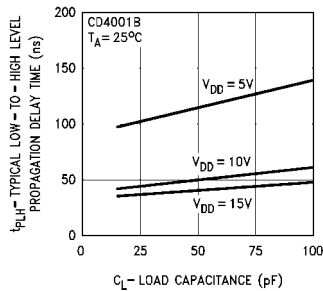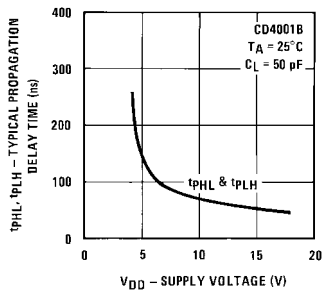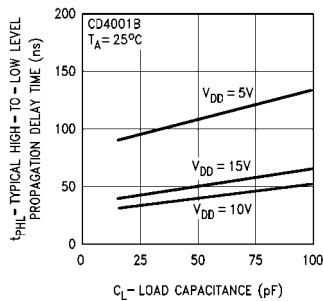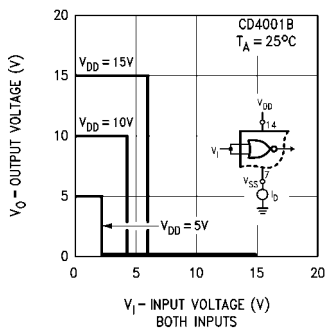| Symbol	Parameter	Conditions	Typ	Max	Units
t_{PHL}	Propagation Delay, HIGH-to-LOW Level	V_{DD} = 5V	120	250	
		V_{DD} = 10V	50	100	ns
		V_{DD} = 15V	35	70	
t_{PLH}	Propagation Delay, LOW-to-HIGH Level	V_{DD} = 5V	85	250	
		V_{DD} = 10V	40	100	ns
		V_{DD} = 15V	30	70	
t_{THL}, t_{TLH}	Transition Time	V_{DD} = 5V	90	200	
		V_{DD} = 10V	50	100	ns
		V_{DD} = 15V	40	80	
C_{IN}	Average Input Capacitance	Any Input	5	7.5	pF
C_{PD}	Power Dissipation Capacity	Any Gate	14		pF

Note 5: AC Parameters are guaranteed by DC correlated testing.

Typical Performance Characteristics

Typical Transfer Characteristics

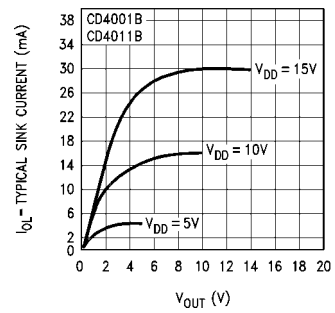**Typical Transfer Characteristics**
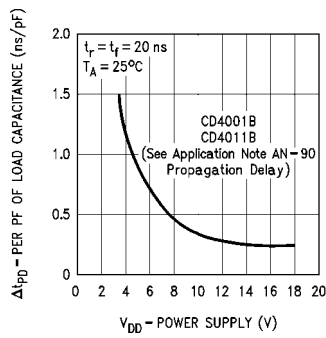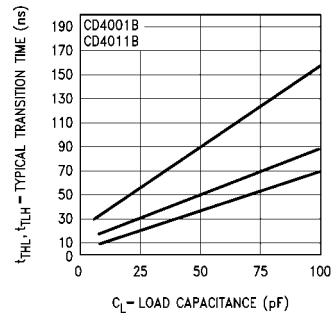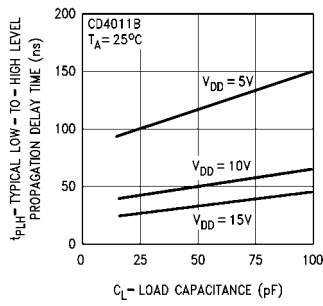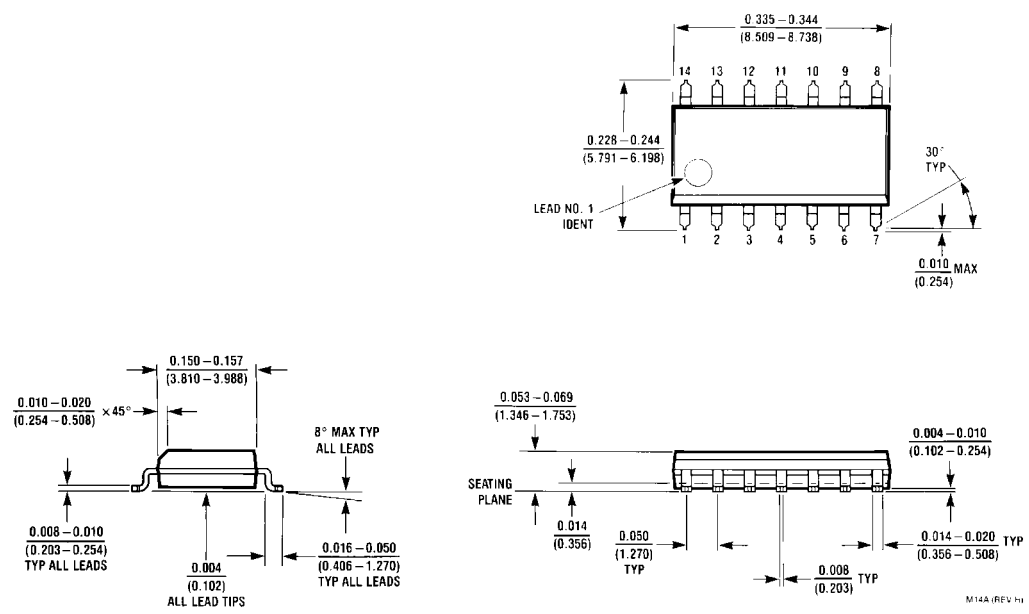

Typical Transfer Characteristics
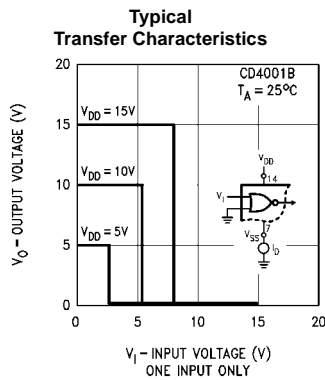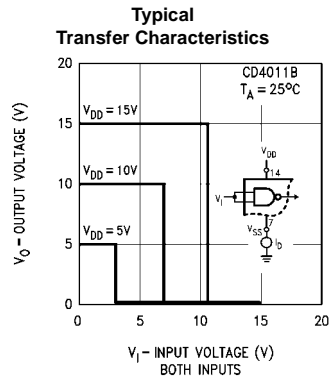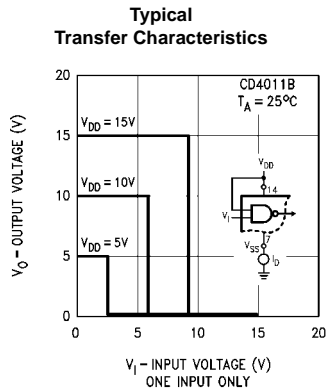
Typical Performance Characteristics (Continued)

Typical Transfer Characteristics

CD4001BC/CD4011BC

Typical Performance Characteristics (Continued)

t_{PLH} – TYPICAL LOW – TO – HIGH LEVEL PROPAGATION DELAY TIME (ns) vs C_L – LOAD CAPACITANCE (pF)

CD4011B
$T_A = 25°C$

$V_{DD} = 5V$
$V_{DD} = 10V$
$V_{DD} = 15V$

t_{THL}, t_{TLH} – TYPICAL TRANSITION TIME (ns) vs C_L – LOAD CAPACITANCE (pF)

CD4001B
CD4011B

Δt_{PD} – PER pF OF LOAD CAPACITANCE (ns/pF) vs V_{DD} – POWER SUPPLY (V)

$t_r = t_f = 20$ ns
$T_A = 25°C$

CD4001B
CD4011B
(See Application Note AN–90 Propagation Delay)

I_{OL} – TYPICAL SINK CURRENT (mA) vs V_{OUT} (V)

CD4001B
CD4011B

$V_{DD} = 15V$
$V_{DD} = 10V$
$V_{DD} = 5V$

I_{OH} – TYPICAL SOURCE CURRENT (mA) vs $V_{CC} - V_{OUT}$ (V)

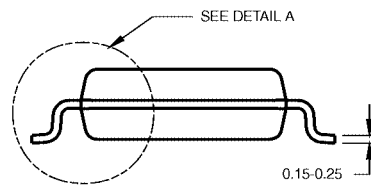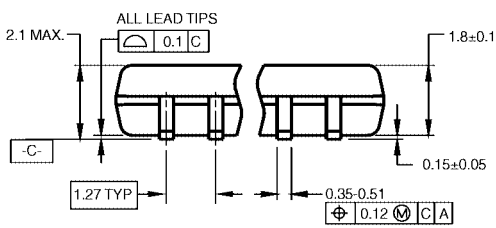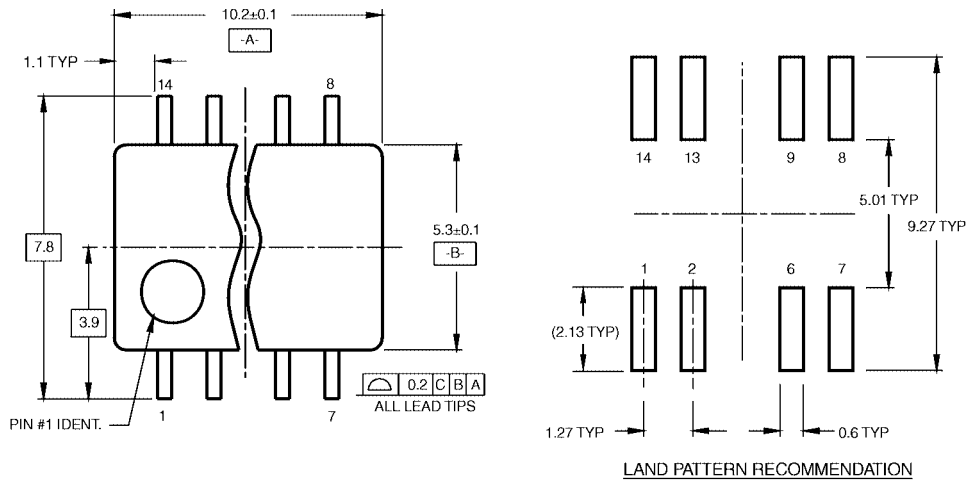$V_{CC} = 5V$
$V_{CC} = 10V$
$V_{CC} = 15V$

Physical Dimensions inches (millimeters) unless otherwise noted

14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
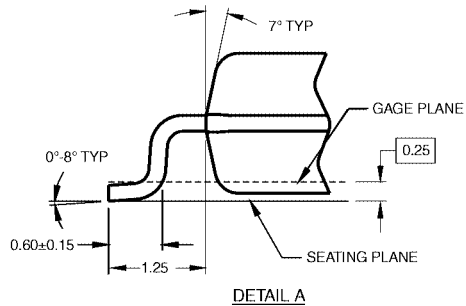**Package Number M14A**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

10.2±0.1
-A-

1.1 TYP

14   8

7.8

3.9

5.3±0.1
-B-

⌒ 0.2 C B A
ALL LEAD TIPS

PIN #1 IDENT.   1   7

14   13   9   8

5.01 TYP
9.27 TYP

(2.13 TYP)

1   2   6   7

1.27 TYP   0.6 TYP

LAND PATTERN RECOMMENDATION

ALL LEAD TIPS

2.1 MAX.   ⌒ 0.1 C

-C-

1.27 TYP

0.35-0.51
⊕ 0.12 Ⓜ C A

1.8±0.1

0.15±0.05

DIMENSIONS ARE IN MILLIMETERS

SEE DETAIL A

0.15-0.25

NOTES:
A. CONFORMS TO EIAJ EDR-7320 REGISTRATION,
    ESTABLISHED IN DECEMBER, 1998.
B. DIMENSIONS ARE IN MILLIMETERS.
C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD
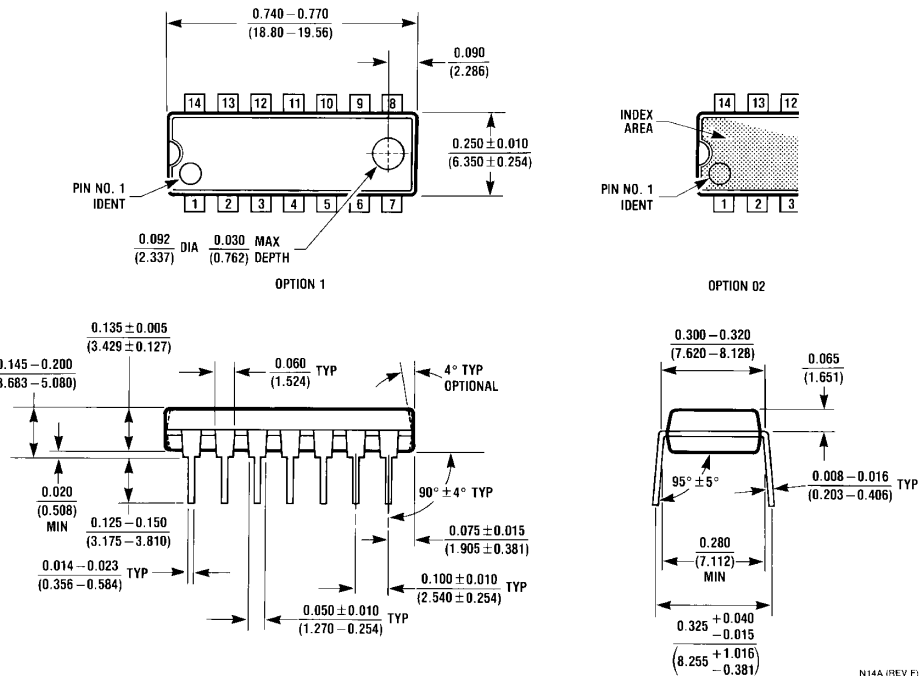   FLASH, AND TIE BAR EXTRUSIONS.

M14DRevB1

7° TYP

GAGE PLANE

0.25

0°-8° TYP

0.60±0.15

1.25

SEATING PLANE

DETAIL A

14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M14D

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N14A

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2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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